Gerald Rescher

List of Publications by Year in descending order

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2258059 2053705 8 321 3 5 citations h-index g-index papers 8 8 8 248 docs citations times ranked citing authors all docs

#	Article	IF	CITATIONS
1	On the origin of drain current transients and subthreshold sweep hysteresis in 4H-SiC MOSFETs. Applied Physics Letters, 2019, 115, .	3.3	2
2	NH ₃ and NO + NH ₃ Annealing of 4H-SiC Trench MOSFETs: Device Performance and Reliability. IEEE Transactions on Electron Devices, 2019, 66, 4692-4697.	3.0	12
3	Threshold voltage peculiarities and bias temperature instabilities of SiC MOSFETs. Microelectronics Reliability, 2018, 80, 68-78.	1.7	160
4	Investigation of threshold voltage stability of SiC MOSFETs. , 2018, , .		46
5	Preconditioned BTI on 4H-SiC: Proposal for a Nearly Delay Time-Independent Measurement Technique. IEEE Transactions on Electron Devices, 2018, 65, 1419-1426.	3.0	35
6	Improved Interface Trap Density Close to the Conduction Band Edge of a-Face 4H-SiC MOSFETs Revealed Using the Charge Pumping Technique. Materials Science Forum, 2017, 897, 143-146.	0.3	3
7	On the subthreshold drain current sweep hysteresis of 4H-SiC nMOSFETs. , 2016, , .		40
8	Threshold Voltage Instabilities of Present SiC-Power MOSFETs under Positive Bias Temperature Stress. Materials Science Forum, 0, 858, 481-484.	0.3	23